Hg[CS(NH₂)₂]₄(SiF₆): A Fluorosilicate Crystal with Large Birefringence Achieved via Multi-Functional Group Modification

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S1. Experimental Section

Materials and Instrumentations.

All the chemicals were obtained from commercial sources and used without further purification: CS(NH₂)₂ (Adamas-beta, 99%), Hg(CF₃SO₃)₂ (Adamas-beta, 98%), and H₂SiF₆ (Adamas-beta, 30% in water).

Powder X-ray diffraction (PXRD) patterns of Hg[CS(NH₂)₂]₄(SiF₆) was collected on the Miniflex 600 powder X-ray diffractometer using Cu K α radiation ($\lambda = 1.54186$ Å) at room temperature in the angular range of $2\theta = 5-70^{\circ}$ with a scan step size of 0.02° .

Microprobe elemental analysis was carried out with the aid of a field-emission scanning electron microscope (JSM6700F) outfitted with an energy-dispersive X-ray spectroscope (Oxford INCA).

IR spectra were carried out on a Magna 750 FT-IR spectrometer using air as background in the range of 4000–400 cm⁻¹ with a resolution of 2 cm⁻¹ at room temperature.

The UV-vis-NIR spectra were obtained at 2000-200 nm by a PerkinElmer Lambda 900 spectrophotometer using BaSO₄ as the reference, and the reflection spectra were converted into an absorption spectrum using the Kubelka-Munk function. Absorption data was calculated from the diffuse reflection data by the Kubelka-Munk function: $\alpha/S = (1-R)^2/2R$, where α and S represent the absorption coefficient and the scattering coefficient, respectively. The band gap value can be given by extrapolating the absorption edge to the baseline in the α/S vs. energy graph.

Thermogravimetric analyses (TGA) and differential scanning calorimetry (DSC) were measured by Netzsch STA 499C installation. The samples about 3.0-5.0 mg were placed in alumina crucibles and heated in 20-700 °C at a rate of 15 °C/min under N_2 atmosphere.

Single-crystal X-ray diffraction data was obtained on Agilent Technologies SuperNova dual-wavelength CCD diffractometer with a graphite-monochromated Mo K α radiation (λ = 0.71073 Å) at room temperature. Data reduction and cell refinement and were performed with *CrysAlisPro*. The structure was solved by the direct methods and refined by full-matrix least-

squares fitting on F^2 using OLEX2-1.5 crystallographic software package. All non-hydrogen atoms were refined with anisotropic thermal parameters. The structural data were also checked by PLATON and no higher symmetry was found. The detailed crystallographic data for $Hg[CS(NH_2)_2]_4(SiF_6)$ was given in Table S1. The bond lengths and bond angles were listed in Table S2 and S4.

S2. Computational Method

Single-crystal structural data of Hg[CS(NH₂)₂]₄(SiF₆) was used for the theoretical calculations. The electronic structures were performed using a plane-wave basis set and pseudo-potentials within density functional theory (DFT) implemented in the total-energy code CASTEP¹. For the exchange and correlation functional, we chose Perdew-Burke-Ernzerhof (PBE) in the generalized gradient approximation (GGA)². The interactions between the ionic cores and the electrons were described by the Nom-conserving pseudopotential in reciprocal space³. The following valence-electron configurations were considered in the computation: Hg-5d¹⁰5p²6s², C-2s²2p², S-3s²3p⁴, N-2s²2p³, H-1s², Si-3s²3p² and F-2s²2p⁵. The numbers of plane waves included in the basics sets were determined by cutoff energy of 850 eV for Hg[CS(NH₂)₂]₄(SiF₆). The Brillouin zone integration was performed using a 2×2×2 Monkhorst-Pack k-point mesh, whose convergence was verified against denser k-point samplings. All other calculation parameters and convergence criteria were set to the CASTEP code defaults.

The calculations of linear optical properties in terms of the complex dielectric function $\varepsilon(\omega)$ = $\varepsilon_1(\omega)$ + i $\varepsilon_2(\omega)$ were made. The imaginary part of the dielectric function ε 2 was given in the following equation:

$$\epsilon^{ij}_{2}(\omega) = \frac{8\pi^{2}h^{2}e^{2}}{(m^{2}V)} \sum_{k} \sum_{cv} (f_{c} - f_{v}) \frac{p_{cv}^{i}(k)p_{cv}^{j}(k)}{E_{vc}^{2}} \delta[E_{c(k)} - E_{v(k)-h\omega}]$$

The f_c and f_v represent the Fermi distribution functions of the conduction and valence band. The term $p^i_{cv}(k)$ denotes the momentum matrix element transition from the energy level c of the conduction band to the level v of the valence band at the kth point in the Brillouin zone (BZ), and V is the volume of the unit cell.

The real part $\varepsilon_1(\omega)$ of the dielectric function $\varepsilon(\omega)$ follows from the Kramer-Kronig relationship. All the other optical constants may be derived from $\varepsilon_1(\omega)$ and $\varepsilon_2(\omega)$. For example, the refractive index $n(\omega)$ can be calculated using the following expression⁴:

$$n(\omega) \!\!=\!\! (\overline{\sqrt{2}}) [\sqrt{\epsilon_1^2(\omega) + \,\epsilon_2^2(\omega)} + \!\!\epsilon_1(\omega)]^{1/2}$$

Furthermore, a sensitivity analysis of the scissor operator was conducted. The calculated birefringence values were 0.120 @1064 nm and 0.139 @546 nm with a 0.3 eV scissor operator, and 0.130 @1064 nm and 0.115 @546 nm with a 0.6 eV operator.

Table S1. Summary of crystal data and structural refinements for $Hg[CS(NH_2)_2]_4(SiF_6)$.

| Molecular formula | $Hg[CS(NH_2)_2]_4(SiF_6)$ |
|---|--|
| Formula Weight | 647.17 |
| Crystal system | monoclinic |
| Space group | $P2_1/c$ |
| Temperature (K) | 296.15 |
| F(000) | 1232.0 |
| a/Å | 11.9952(8) |
| b/Å | 13.2312(8) |
| c/Å | 11.8979(10) |
| α/deg | 90 |
| β/deg | 104.765(7) |
| γ/deg | 90 |
| $V/Å^3$ | 1826.0(2) |
| Z | 4 |
| $D_{calc}/g \cdot cm^{-3}$ | 2.354 |
| GOF on F ² | 1.028 |
| $R_1, wR_2[I > 2\sigma(I)]^{\alpha}$ | $R_1 = 0.0344, wR_2 = 0.0753$ |
| R_1 , w R_2 (all data) $^{\alpha}$ | $R_1 = 0.0433, wR_2 = 0.0812$ |
| ${}^{a}R_{1} = \sum F_{o} - F_{c} / \sum F_{o} , wR_{2} =$ | $\{\sum w[(F_o)^2 - (F_c)^2]^2 / \sum w[(F_o)^2]^2\}^{-1/2}$ |

Table S2. Selected bond distances (Å) for Hg[CS(NH₂)₂]₄(SiF₆).

| Bond | Bond lengths |
|---------------|--------------|
| Hg(1)-S(1) | 2.545(2) |
| Hg(1)-S(2) | 2.594(18) |
| Hg(1)-S(3) | 2.555(18) |
| Hg(1)-S(4) | 2.493(17) |
| Si(1)-F(1) | 1.691(4) |
| Si(1)- $F(2)$ | 1.659(5) |
| Si(1)- $F(3)$ | 1.665(5) |
| Si(1)- $F(4)$ | 1.686(4) |
| Si(1)- $F(5)$ | 1.669(5) |
| Si(1)-F(6) | 1.682(5) |
| C(1)-N(1) | 1.308(9) |
| C(1)-N(2) | 1.307(9) |
| C(1)-S(1) | 1.733(7) |
| C(2)-N(3) | 1.303(9) |
| C(2)-N(4) | 1.309(9) |
| C(2)-S(2) | 1.735(7) |
| C(3)-N(5) | 1.310(8) |
| C(3)-N(6) | 1.304(9) |
| C(3)-S(3) | 1.750(7) |
| C(4)-N(7) | 1.321(9) |
| C(4)-N(8) | 1.308(9) |
| C(4)-S(4) | 1.720(7) |

Table S3. Atomic coordinates ($\times 10^4$) and equivalent isotropic displacement parameters ($\mathring{A}^2 \times 10^3$) for Hg[CS(NH₂)₂]₄(SiF₆). U_{eq} is defined as 1/3 of the trace of the orthogonalised U_{ij} tensor.

| Atom | x | y | z | U(eq) |
|------|------------|------------|-------------|-----------|
| Hg1 | 5272.2(2) | 4786.6(2) | 12420.9(2) | 33.91(12) |
| S4 | 3238.6(14) | 4207.3(12) | 11685.3(16) | 31.0(4) |
| S3 | 5577.3(16) | 6682.3(13) | 12777.9(16) | 34.0(4) |
| S2 | 6072.3(16) | 3849.7(13) | 14375.0(15) | 33.8(4) |
| S1 | 6200.4(17) | 4162.5(15) | 10849.7(17) | 39.2(4) |
| Si1 | 345.8(15) | 2282.1(14) | 9460.1(17) | 28.3(4) |
| F1 | -1108(3) | 2201(3) | 9043(4) | 40.4(10) |
| F4 | 1798(3) | 2343(3) | 9859(4) | 45.3(11) |
| F2 | 310(4) | 3220(4) | 8525(5) | 72.3(17) |
| F3 | 246(4) | 3106(4) | 10487(5) | 67.0(15) |
| F5 | 403(4) | 1337(4) | 10402(5) | 64.2(15) |
| N5 | 7687(5) | 6839(4) | 12496(5) | 36.8(14) |
| N4 | 6806(6) | 5570(5) | 15485(5) | 39.8(15) |
| F6 | 459(4) | 1426(4) | 8449(5) | 68.3(16) |
| N6 | 6238(5) | 6974(5) | 10840(5) | 38.3(15) |
| N7 | 2680(5) | 6170(5) | 11772(6) | 45.3(17) |
| C3 | 6588(6) | 6843(5) | 11960(6) | 26.5(14) |
| C2 | 7095(6) | 4739(5) | 15031(6) | 29.3(15) |
| N3 | 8182(6) | 4576(5) | 15102(7) | 54(2) |
| N2 | 8327(5) | 4446(5) | 12185(6) | 48.5(17) |
| N1 | 8001(6) | 2970(5) | 11199(6) | 52.9(19) |
| N8 | 1217(5) | 5045(5) | 11291(7) | 57(2) |
| C4 | 2326(6) | 5226(5) | 11576(6) | 31.1(15) |
| C1 | 7620(6) | 3835(5) | 11483(6) | 32.9(16) |

 $\textbf{Table S4}. \ Selected \ bond \ angles \ for \ Hg[CS(NH_2)_2]_4(SiF_6).$

| Atom | Atom | Atom | Angle/° | Atom | Atom | Atom | Angle/° |
|------|------|------|-----------|------|------|------|----------|
| S4 | Hg1 | S3 | 116.49(6) | F3 | Si1 | F6 | 178.5(3) |
| S4 | Hg1 | S2 | 105.85(6) | F5 | Si1 | F1 | 90.7(2) |
| S4 | Hg1 | S1 | 102.38(6) | F5 | Si1 | F4 | 89.1(2) |
| S3 | Hg1 | S2 | 108.40(6) | F5 | Si1 | F6 | 88.8(3) |
| S1 | Hg1 | S3 | 111.70(6) | F6 | Si1 | F1 | 90.7(2) |
| S1 | Hg1 | S2 | 111.85(6) | F6 | Si1 | F4 | 88.2(2) |
| C4 | S4 | Hg1 | 109.4(2) | N5 | C3 | S3 | 118.9(5) |
| C3 | S3 | Hg1 | 96.7(2) | N6 | C3 | S3 | 119.8(5) |
| C2 | S2 | Hg1 | 97.8(2) | N6 | C3 | N5 | 121.4(6) |
| C1 | S1 | Hg1 | 109.1(2) | N4 | C2 | S2 | 121.6(6) |
| F4 | Sil | F1 | 178.9(3) | N3 | C2 | S2 | 119.8(6) |
| F2 | Si1 | F1 | 90.1(2) | N3 | C2 | N4 | 118.5(7) |
| F2 | Si1 | F4 | 90.1(3) | N7 | C4 | S4 | 123.9(5) |
| F2 | Si1 | F3 | 90.5(3) | N8 | C4 | S4 | 117.5(5) |
| F2 | Si1 | F5 | 179.2(3) | N8 | C4 | N7 | 118.6(7) |
| F2 | Sil | F6 | 91.0(3) | N2 | C1 | S1 | 122.0(6) |
| F3 | Sil | F1 | 89.7(2) | N2 | C1 | N1 | 119.6(7) |
| F3 | Si1 | F4 | 91.4(2) | N1 | C1 | S1 | 118.4(6) |
| F3 | Si1 | F5 | 89.8(3) | | | | |

Table S5. State energies (eV) of the lowest conduction band (L-CB) and the highest valence band (H-VB) of $Hg[CS(NH_2)_2]_4(SiF_6)$.

| Compound | k-point | L-CB | H-VB |
|---------------------------|--------------------------|----------|----------|
| | Z (0.000, 0.000, 0.500) | 3.036249 | -0.00655 |
| | G (0.000, 0.000, 0.000) | 2.979945 | -0.0194 |
| | Y (0.000, 0.500, 0.000) | 3.018859 | -0.04572 |
| H-ICCONH) 1 (CE) | A (-0.500, 0.500, 0.000) | 3.018254 | -0.05825 |
| $Hg[CS(NH_2)_2]_4(SiF_6)$ | B (-0.500, 0.000, 0.000) | 2.979949 | -0.03092 |
| | D (-0.500, 0.000, 0.500) | 3.031659 | -0.01947 |
| | E (-0.500, 0.500, 0.500) | 3.05326 | -0.01361 |
| | C (0.000, 0.500, 0.500) | 3.052199 | 0 |

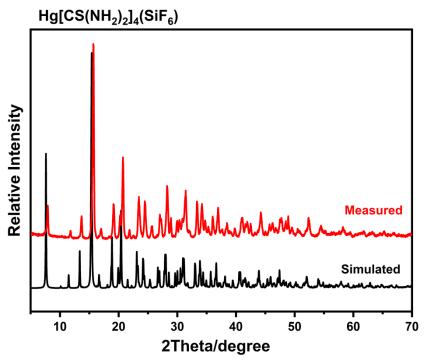


Figure S1. Simulated and experimental powder X-ray diffractometer patterns of $Hg[CS(NH_2)_2]_4(SiF_6)$.

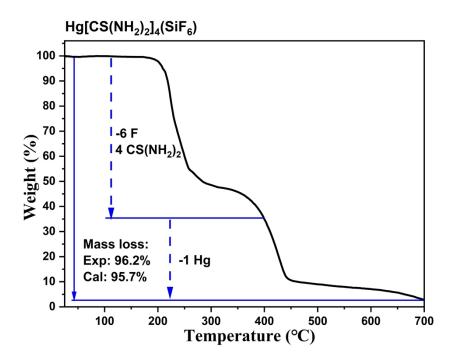


Figure S2. The thermal stability curves of $Hg[CS(NH_2)_2]_4(SiF_6)$.

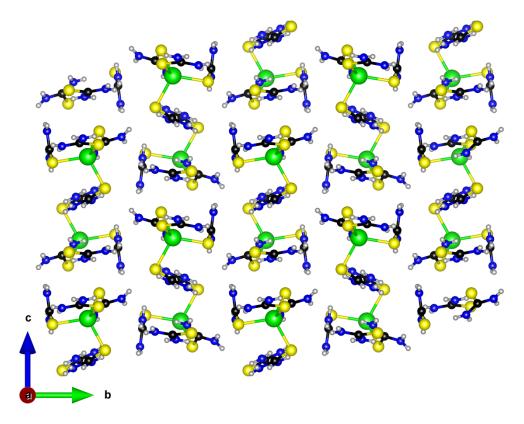


Figure S3. Arrangement of the $CS(NH_2)_2$ groups in $Hg[CS(NH_2)_2]_4(SiF_6)$.

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